

# FDD6688S

# **30V N-Channel PowerTrench® SyncFET™**

### **General Description**

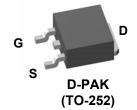
The FDD6688S is designed to replace a single TO-252 MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low  $R_{\text{DS(ON)}}$  and low gate charge. The FDD6688S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

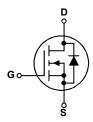
### Applications

- DC/DC converter
- Motor Drives

#### **Features**

- 88 A, 30 V.  $R_{DS(ON)} = 5.1 \ m\Omega \ @V_{GS} = 10 \ V$   $R_{DS(ON)} = 6.3 \ m\Omega \ @V_{GS} = 4.5 \ V$
- Low gate charge (31 nC typical)
- · Fast switching
- High performance trench technology for extremely low  $R_{\mbox{\scriptsize DS(ON)}}$





### Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	V
$V_{GSS}$	Gate-Source Voltage		± 20	
I <sub>D</sub>	Drain Current - Continuous	(Note 3)	88	Α
	- Pulsed	(Note 1a)	100	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1)	69	W
		(Note 1a)	3.1	
		(Note 1b)	1.3	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	
		(Note 1b)	96	

**Package Marking and Ordering Information** 

Device Marking	Device	Package	Reel Size Tape width		Quantity	
FDD6688S	FDD6688S	D-PAK (TO-252)	13"	12mm	2500 units	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Avalanche Ratings (No	te 2)	1			
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, V <sub>DD</sub> = 15 V, I <sub>D</sub> = 21A		501		mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				21	Α
Off Char	acteristics				<u>I</u>	
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 1\text{mA}$	30			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 15mA, Referenced to 25°C		30		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			500	μА
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V},  V_{DS} = 0 \text{ V}$			± 100	nA
On Char	acteristics (Note 2)		•	•		
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1mA$	1	1.4	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 15mA, Referenced to 25°C		-0.3		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 18.5 A V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 16.5 A V <sub>GS</sub> = 10 V, I <sub>D</sub> = 18.5 A, T <sub>J</sub> =125°C		4.0 4.7 6.0	5.1 6.3 7.5	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 18.5 A		72		S
Dynamic	Characteristics		1			
C <sub>iss</sub>	Input Capacitance			3290		pF
Coss	Output Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		900		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1.0 MHz		300		pF
Rg	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.6		Ω
Switchin	g Characteristics (Note 2)			l		
t <sub>d(on)</sub>	Turn-On Delay Time			13	23	ns
t <sub>r</sub>	Turn–On Rise Time	$V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$		13	23	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		31	50	ns
t <sub>f</sub>	Turn-Off Fall Time			64	103	ns
Q <sub>g(TOT)</sub>	Total Gate Charge at Vgs=10V			58	81	nC
Q <sub>g</sub>	Total Gate Charge at Vgs=5V	1, 45, 1, 40,5,		31	44	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{DD} = 15 \text{ V},  I_D = 18.5 \text{ A}$		8		nC
$Q_{gd}$	Gate-Drain Charge			10		nC

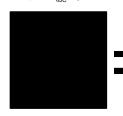
### **Electrical Characteristics** (continued)

T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Diode Characteristics	and Maximum Ratings				
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 4.4 \text{ A}  \text{(Note 2)}$		400	700	mV
t <sub>rr</sub>	Diode Reverse Recovery Time			28		ns
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$I_F = 18.5 \text{ A},  d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$		30		nC
Im	Diode Reverse Recovery Current			2.1		Α

#### Notes:8

 R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>8JC</sub> is guaranteed by design while R<sub>8CA</sub> is determined by the user's board design.



a)  $R_{\theta,JA} = 40^{\circ}\text{C/W}$  when mounted on a  $1\text{in}^2$  pad of 2 oz copper



b)  $R_{\theta JA} = 96^{\circ}C/W$  when mounted on a minimum pad.

Scale 1:1 on letter size paper

**2.** Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

3. Maximum current is calculated as:  $\sqrt{\frac{P_D}{R_{DS(ON)}}}$ 

where  $P_D$  is maximum power dissipation at  $T_C$  = 25°C and  $R_{DS(on)}$  is at  $T_{J(max)}$  and  $V_{GS}$  = 10V. Package current limitation is 21A

### **Typical Characteristics**

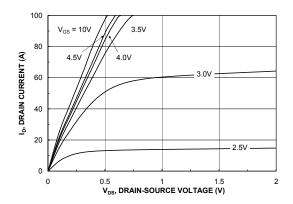


Figure 1. On-Region Characteristics.

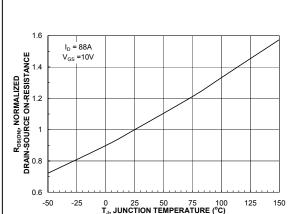


Figure 3. On-Resistance Variation with Temperature.

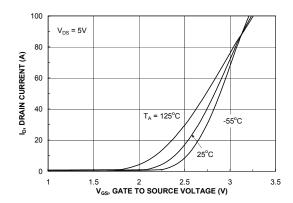


Figure 5. Transfer Characteristics

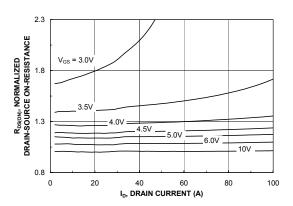


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

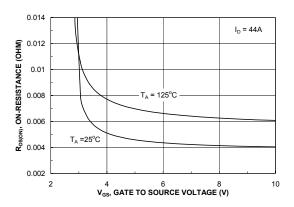


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

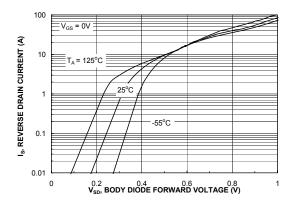
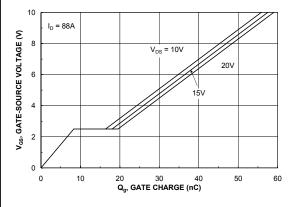


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

## **Typical Characteristics**



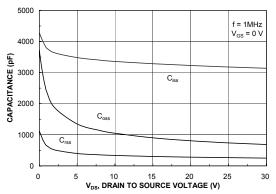
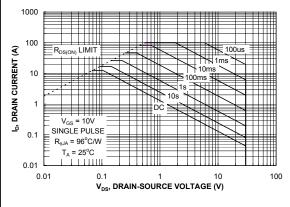


Figure 7. Gate Charge Characteristics





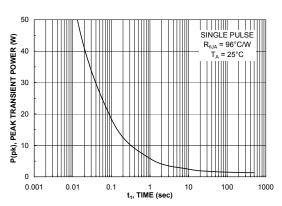


Figure 9. Maximum Safe Operating Area

Figure 10. Single Pulse Maximum Power Dissipation

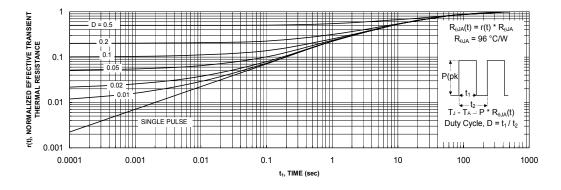


Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

### Typical Characteristics (continued)

# **SyncFET Schottky Body Diode Characteristics**

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDD6688S.

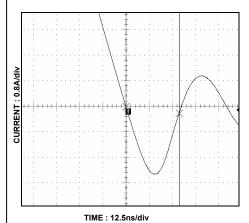


Figure 12. FDD6688S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDD6688).

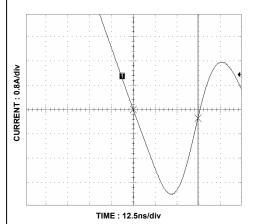


Figure 13. Non-SyncFET (FDD6688) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

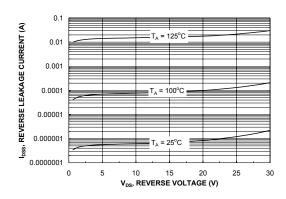
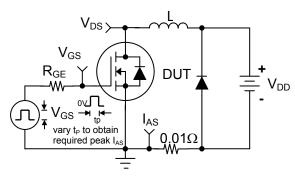


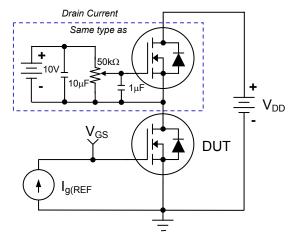
Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.



BV<sub>DSS</sub>
V<sub>DS</sub>
V<sub>DD</sub>
V<sub>DD</sub>

Figure 15. Unclamped Inductive Load Test Circuit

Figure 16. Unclamped Inductive Waveforms



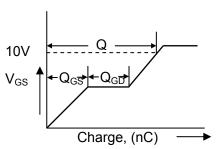
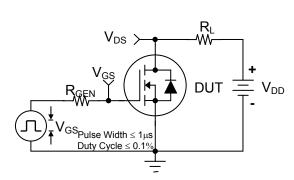


Figure 17. Gate Charge Test Circuit

Figure 18. Gate Charge Waveform



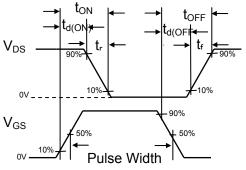


Figure 19. Switching Time Test Circuit

Figure 20. Switching Time Waveforms

### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

$ACEx^{TM}$	FAST®	ISOPLANAR™	Power247™	SuperFET™
ActiveArray™	FASTr™	LittleFET™	PowerSaver™	SuperSOT™-3
Bottomless™	FPS™	$MICROCOUPLER^{TM}$	PowerTrench®	SuperSOT™-6
CoolFET™	FRFET™	MicroFET™	QFET®	SuperSOT™-8
$CROSSVOLT^{\text{TM}}$	GlobalOptoisolator™	MicroPak™	$QS^{TM}$	SyncFET™
DOME™	GTO™ .	MICROWIRE™	QT Optoelectronics™	TinyLogic <sup>®</sup>
EcoSPARK™	HiSeC™	MSXTM	Quiet Series™	TINYOPTO™
E <sup>2</sup> CMOS <sup>TM</sup>	I <sup>2</sup> C <sup>TM</sup>	MSXPro™	RapidConfigure™	TruTranslation™
EnSigna™	<i>i-</i> Lo <sup>™</sup>	$OCX^{TM}$	RapidConnect™	UHC™
FACT™	ImpliedDisconnect™	OCXPro™	μSerDes™	UltraFET®
FACT Quiet Serie	es <sup>™</sup>	OPTOLOGIC®	SILENT SWITCHER®	VCX <sup>TM</sup>
Across the board	d. Around the world.™	OPTOPLANAR™	SMART START™	
The Power France		PACMAN™	SPM <sup>TM</sup>	
			<u> </u>	

#### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

POPTM

#### LIFE SUPPORT POLICY

 $Programmable \ Active \ Droop^{\tiny\mathsf{TM}}$ 

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

Stealth™

#### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Datasheet Identification		Definition		
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.		
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.		
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.		
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.		

Rev. I11